

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/692,729	TATEIWA, AKIHIKO
	<b>Examiner</b>	<b>Art Unit</b>
	Mike Stahl	2874

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner